Device Modeling Report

COMPONENTS: OPERATIONAL AMPLIFIER (CMOS)

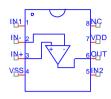
PART NUMBER: NJU7051

MANUFACTURER: NEW JAPAN RADIO



Bee Technologies Inc.

SPICE MODEL



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*PART NUMBER: NJU7051
*MANUFACTURER: NEW JAPAN RADIO
*CMOS OPAMP
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                  IN- IN+ IN1 IN2 VDD VSS OUT
.SUBCKT niu7051
M1
           2 IN- 3 VDD MbreakPD3
M2
           2 IN+ 4 VDD MbreakPD2
           VDD 1 2 VDD MbreakPD
M3
M4
           VDD 1 5 VDD MbreakPD
M5
          VDD 1 6 VDD MbreakPD
M6
           VDD 1 1 VDD MbreakPD
           5 5 VSS VSS MbreakND W=3.2m
M7
                                           L=6u
M8
           5 4 VSS VSS MbreakND3
M9
           3 3 IN1 VSS MbreakND1
           4 3 IN2 VSS MbreakND1
M10
M11
           1 6 11 11 MbreakND
                                 W=9m
                                         L=6u
M12
           6 6 VSS VSS MbreakND3
M13
           7 5 VSS VSS MbreakND1
M14
           VDD 7 7 VDD MbreakPD
M15
           VDD 7 OUT VDD MbreakPD1
M16
           OUT 4 VSS VSS MbreakND2
C1
          OUT 1 1p
C2
          OUT IN-30p
C3
          OUT 5 100p
R1
          11 VSS 1.522k
R2
          IN1 VSS 2.0k
R3
          IN2 VSS 2.423k
11
          0 IN- 0.505p
12
          0 IN+ 1.5p
X U1
           VSS 3 DbreakZ
           VSS 4 DbreakZ
X U2
```

- .model MbreakND NMOS (LEVEL=3 VTO=0.9 RS=10.000E-3 RD=10.00E-3
- + RDS=1.0000E6 TOX=2.0000E-6 CGSO=4.000E-12 CGDO=1.000E-12
- + CBD=1.000E-12 RG=5 RB=1.0000E-3 KP=10E-6)
- .model MbreakND1 NMOS (LEVEL=3 L=6u W=0.5 VTO=1 RS=10.000E-3
- + RD=10.000E-3 RDS=1.0000E6 TOX=2.0000E-6 CGSO=3.00E-12
- + CGDO=1.000E-12 CBD=1.000E-12 RG=5 RB=1.0000E-3 KP=10E-6)
- .model MbreakND2 NMOS (LEVEL=3 L=6u W=0.483m VTO=0.9 RS=10.000E-3
- + RD=10.000E-3 RDS=1.0000E6 TOX=2.0000E-6 CGSO=4.000E-12
- + CGDO=1.00E-12 CBD=1.000E-12 RG=5 RB=1.0000E-3 KP=10E-6) .model MbreakND3 NMOS (LEVEL=3 L=6u W=3.2m VTO=0.9 RS=10.000E-3
- + RD=10.000E-3 RDS=1.0000E6 TOX=2.0000E-6 CGSO=3.4000E-7
- + CGDO=1.000E-12 CBD=1.000E-5 RG=5 RB=1.0000E-3 KP=10E-6) .model MbreakPD PMOS (LEVEL=3 L=6u W=0.023 VTO=-1 RS=10.000E-3
- + RD=10.000E-3 RDS=1.0000E6 TOX=2.0000E-6 CGSO=4.000E-12
- + CGDO=1.000E-12 CBD=1.000E-12 RG=5 RB=1.0000E-3 KP=1E-6)
- .MODEL MbreakPD1 PMOS (LEVEL=3 L=6u W=0.0056 VTO=-0.9 RS=10.000E-3
- + RD=10.000E-3 RDS=1.00E6 TOX=2.0000E-6 CGSO=4.000E-12
- + CGDO=1.000E-12 CBD=1.000E-12 RG=5 RB=1.0000E-3 KP=1E-6)
- .MODEL MbreakPD2 PMOS (LEVEL=3 L=6u W=0.13 VTO=-1.5 RS=10.000E-3
- + RD=10.00E-3 RDS=0.900E6 TOX=2.0000E-6 CGSO=4.000E-12
- + CGDO=1.000E-12 CBD=1.00E-12 RG=5 RB=1.0000E-3 KP=1E-6)
- .MODEL MbreakPD3 PMOS (LEVEL=3 L=6u W=0.14 VTO=-1.5 RS=10.000E-3
- + RD=10.00E-3 RDS=1.E6 TOX=2.0000E-6 CGSO=4.000E-12
- + CGDO=1.000E-12 CBD=1.00E-12 RG=5 RB=1.0000E-3 KP=1E-6) .ENDS nju7051

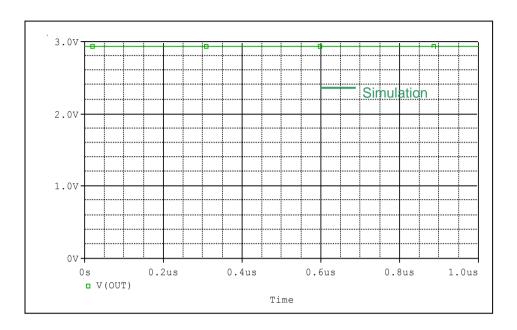
.SUBCKT DbreakZ A K
D1 A K DF
DZ A2 A DR
VZ K A2 1
.MODEL DF D
.MODEL DR D
.ENDS DbreakZ
*\$

MOSFET MODEL

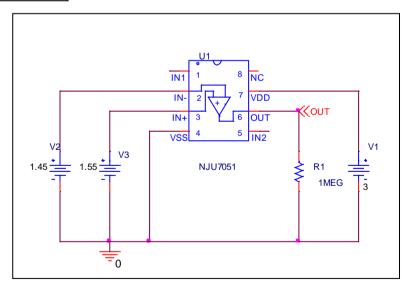
Pspice model	Model description		
parameter			
LEVEL			
L	Channel Length		
W	Channel Width		
KP	Transconductance		
RS	Source Ohmic Resistance		
RD	Ohmic Drain Resistance		
VTO	Zero-bias Threshold Voltage		
RDS	Drain-Source Shunt Resistance		
TOX	Gate Oxide Thickness		
CGSO	Zero-bias Gate-Source Capacitance		
CGDO	Zero-bias Gate-Drain Capacitance		
CBD	Zero-bias Bulk-Drain Junction Capacitance		
MJ	Bulk Junction Grading Coefficient		
PB	Bulk Junction Potential		
FC	Bulk Junction Forward-bias Capacitance Coefficient		
RG	Gate Ohmic Resistance		
IS	Bulk Junction Saturation Current		
N	Bulk Junction Emission Coefficient		
RB	Bulk Series Resistance		
PHI	Surface Inversion Potential		
GAMMA	Body-effect Parameter		
DELTA	Width effect on Threshold Voltage		
ETA	Static Feedback on Threshold Voltage		
THETA	Modility Modulation		
KAPPA	Saturation Field Factor		
VMAX	Maximum Drift Velocity of Carriers		
XJ	Metallurgical Junction Depth		
UO	Surface Mobility		

Output Voltage Swing

Simulation result



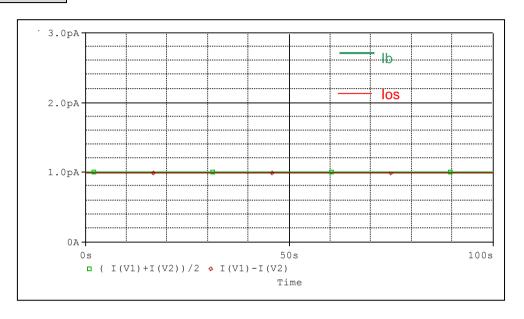
Evaluation Circuit



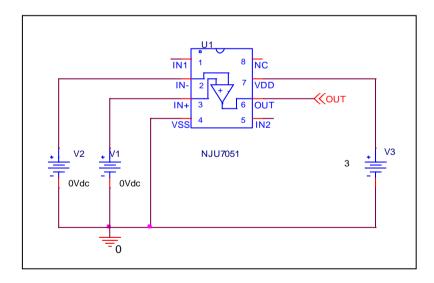
	Measurement	Simulation	%Error
V _{OM} (V)	2.940	2.939	-0.027

Input Current

Simulation result



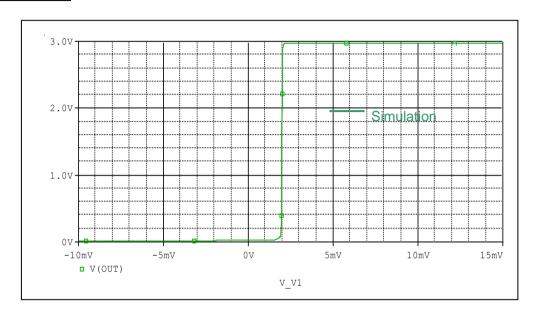
Evaluation Circuit



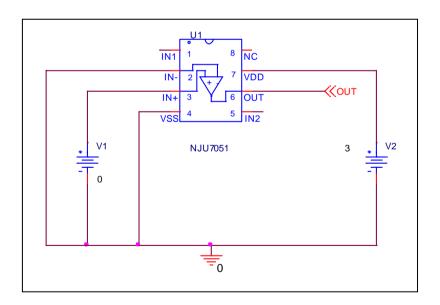
	Measurement	Simulation	% Error
I _b (pA)	1.000	0.995	-0.510
I _{os} (pA)	1.000	1.003	0.250

Input Offset Voltage

Simulation result



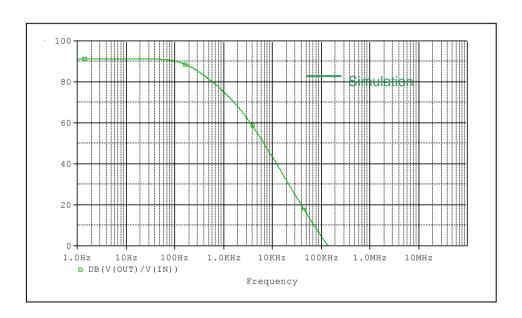
Evaluation Circuit



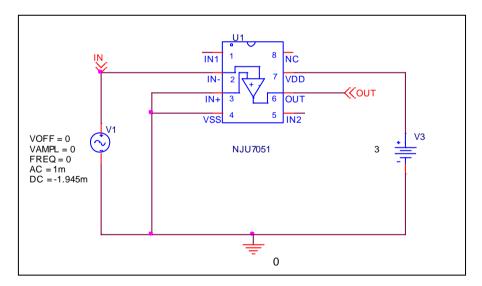
	Measurement	Simulation	%Error
Vos (mV)	2.000	1.945	-2.750

Open loop Voltage Gain

Simulation result



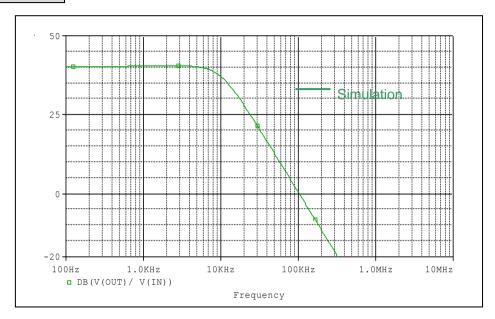
Evaluation Circuit



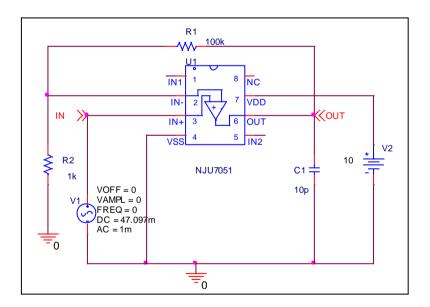
	Measurement	Simulation	%Error
Av (dB)	90.000	91.393	1.548

Unity Gain Frequency

Simulation result



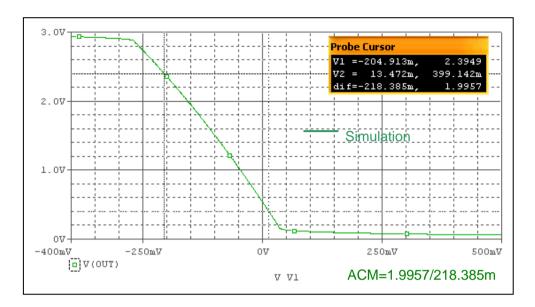
Evaluation Circuit



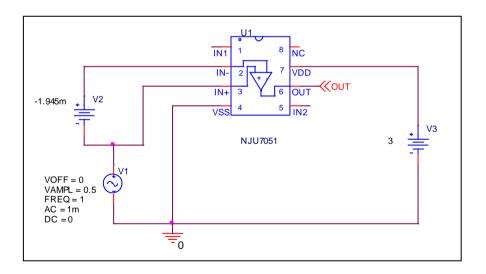
A _V =40dB,C _L =10pF	Measurement	Simulation	%Error
Ft(MHz)	0.100	0.103	3.400

Common-Mode Rejection Ratio

Simulation result



Evaluation Circuit

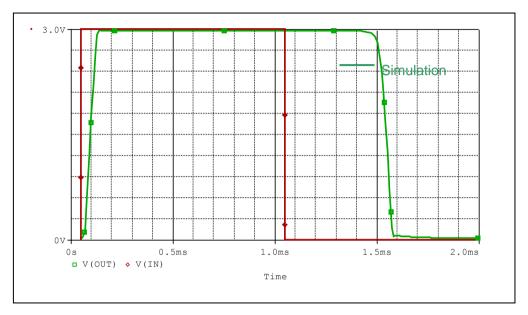


CMRR = AV/ACM

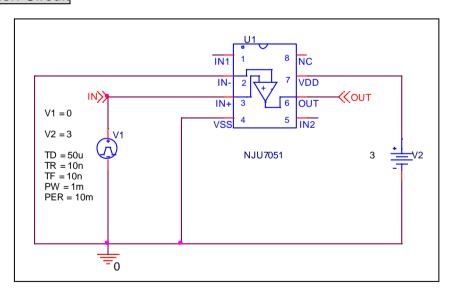
-	Measurement	Simulation	%Error
CMRR (dB)	70.000	72.175	-3.107

Slew Rate

Simulation result



Evaluation Circuit



	Measurement	Simulation	% Error
SR (V/us)	0.050	0.049	-2.200